

**DEPARTMENT OF COMMERCE****International Trade Administration****Ames Laboratory, Et Al. Notice of Consolidated Decision on Applications for Duty-Free Entry of Scientific Instruments**

This is a decision consolidated pursuant to section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89-651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 4211, U.S. Department of Commerce, 14th and Constitution Avenue, NW, Washington, DC.

*Comments:* None received. *Decision:* Approved. No instrument of equivalent scientific value to the foreign instruments described below, for such purposes as each is intended to be used, is being manufactured in the United States.

*Docket Number:* 98-057. *Applicant:* Ames Laboratory, U.S. Department of Energy, Ames, IA 50011-3020.

*Instrument:* Auger Microprobe, Model JAMP-7800F. *Manufacturer:* JEOL Ltd., Japan.

*Intended Use:* See notice at 63 FR 65751, November 30, 1998.

*Reasons:* The foreign instrument provides highest energy resolution of 0.05% with 1.0 nm for secondary electrons and 35nm for Auger analysis. *Advice received from:* National Institute of Standards and Technology, January 13, 1999.

*Docket Number:* 98-063. *Applicant:* University of Maryland, College Park, MD 20742. *Instrument:* Electron Microprobe, Model JXA-8900R. *Manufacturer:* JEOL Ltd., Japan.

*Intended Use:* See notice at 63 FR 69264, December 16, 1998. *Reasons:* The foreign instrument provides characterization of elemental composition and structure in surfaces with resolution down to 1  $\mu$ m. *Advice received from:* National Institute of Standards and Technology, January 13, 1999.

The National Institute of Standards and Technology advises that (1) the capabilities of each of the foreign instruments described above are pertinent to each applicant's intended purpose and (2) it knows of no domestic instrument or apparatus of equivalent scientific value for the intended use of each instrument.

We know of no other instrument or apparatus being manufactured in the United States which is of equivalent

scientific value to either of the foreign instruments.

**Frank W. Creel,**

*Director, Statutory Import Programs Staff.*

[FR Doc. 99-2348 Filed 1-29-99; 8:45 am]

BILLING CODE 3510-DS-P

**DEPARTMENT OF COMMERCE****International Trade Administration****Application for Duty-Free Entry of Scientific Instrument**

Pursuant to Section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89-651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether an instrument of equivalent scientific value, for the purposes for which the instrument shown below is intended to be used, is being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington, DC 20230. Application may be examined between 8:30 A.M. and 5:00 P.M. in Room 4211, U.S. Department of Commerce, 14th Street and Constitution Avenue, NW, Washington, DC.

*Docket Number:* 98-067. *Applicant:* Johns Hopkins University, 3400 N. Charles Street, Baltimore, MD 21218. *Instrument:* Electron Microscope, Model CM300. *Manufacturer:* Philips, The Netherlands. *Intended Use:* The instrument will be used in an electron microscopy laboratory that has been designed to benefit researchers in biomedical engineering, chemical engineering, chemistry, earth and planetary sciences, environmental engineering, materials science and engineering, mechanical engineering and physics. Examples of specific research projects which will be conducted include: (a) Processing and characterization of nanoscale materials, (b) dislocation of core structures in intermetallic alloys, (c) environmental chemistry, (d) development and characterization of rare-earth magnetostictive materials, (e) nanoscale observations of porous semiconductors, (f) identification of failure mechanisms in materials with applications to manufacturing processes and (g) investigations in crystal chemistry and geochemistry. In addition, the instrument will be used to supplement and expand course offerings on electron microscopy, especially analytical based electron microscopy. Application

accepted by Commissioner of Customs: January 4, 1999.

**Frank W. Creel,**

*Director, Statutory Import Programs Staff.*

[FR Doc. 99-2349 Filed 1-29-99; 8:45 am]

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**DEPARTMENT OF COMMERCE****International Trade Administration****Export Trade Certificate of Review**

**ACTION:** Notice of application.

**SUMMARY:** The Office of Export Trading Company Affairs ("OETCA"), International Trade Administration, Department of Commerce, has received an application for an Export Trade Certificate of Review. This notice summarizes the conduct for which certification is sought and requests comments relevant to whether the Certificate should be issued.

**FOR FURTHER INFORMATION CONTACT:** Morton Schnabel, Director, Office of Export Trading Company Affairs, International Trade Administration, (202) 482-5131. This is not a toll-free number.

**SUPPLEMENTARY INFORMATION:** Title III of the Export Trading Company Act of 1982 (15 U.S.C. 4001-21) authorizes the Secretary of Commerce to issue Export Trade Certificates of Review. A Certificate of Review protects the holder and the members identified in the Certificate from state and federal government antitrust actions and from private, treble damage antitrust actions for the export conduct specified in the Certificate and carried out in compliance with its terms and conditions. Section 302(b)(1) of the Act and 15 CFR 325.6(a) require the Secretary to publish a notice in the **Federal Register** identifying the applicant and summarizing its proposed export conduct.

**Request for Public Comments**

Interested parties may submit written comments relevant to the determination whether a Certificate should be issued. If the comments include any privileged or confidential business information, it must be clearly marked and a nonconfidential version of the comments (identified as such) should be included. Any comments not marked privileged or confidential business information will be deemed to be nonconfidential. An original and five copies, plus two copies of the nonconfidential version, should be submitted no later than 20 days after the date of this notice to: Office of Export